Application/Control No. Applicant(s)/Patent Under Reexamination SMITH, DAVID W Examiner Toan D Nguyen Applicant(s)/Patent Under Reexamination SMITH, DAVID W Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,748,688	05-1998	Kim et al.	375/368
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	D	US-			
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